Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/677,341	FUJITA, SHIN
Examiner	Art Unit

David Y. Chung

2871

SEARCHED					
Class	Subclass	Date	Examiner		
349	139	10/3/2005	DC		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
class 349 text search-see search printout	10/3/2005	DC	